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Substitute for Form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Complete if Known

Sheet	1	of	2	Attorney Docket Number	GSIL 0117 PUSA
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U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	U.S. PATENT DOCUMENT		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SMH		4,504,144		Trost	03-12-1985	
		4,710,908		Ohshima et al.	12-01-1987	
		4,820,055		Müller	04-11-1989	
		4,856,053		Hashimoto	08-08-1999	
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		5,386,294		Ototake et al.	01-31-1995	
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		5,502,311		Imai et al.	03-26-1996	
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		US2003/0192866		Han	10-16-2003	
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		US2004/0118821	A1	Han et al.	06-24-2004	
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		Office ³	Number ⁴	Kind Code ⁵ (if known)				
SMH		WO	03/092069	A1	EO Technics Co.	11-06-2003		
SMH		WO	01/61275		GSI Lumonics, Inc.	08-23-2001		
SMH		WO	00/64622		GSI Lumonics Inc.	11-02-2000		

Examiner Signature	S. Heinrich	Date Considered	09-06-05
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.



Substitute for Form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Complete if Known		
			Application Number	10/617,940	
			Filing Date	July 11, 2003	
			First Named Inventor	Joseph P. Downes, et al.	
			Group Art Unit	1725	
			Examiner Name		
Sheet	2	of	2	Attorney Docket Number	GSIL 0117 PUSA 1
OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
SMH		KEIRSTEAD, MARK and SOMERVILLE, PAUL, UV Lasers Are Workhorses, Optoelectronics World magazine, June 2001, pp. 197-198, 200-201, www.optoelectronics-world.com			
		ZAYHOWSKI, JOHN, Q-Switched Microchip Lasers Find Real-World Application, Laser Focus World magazine, August 1999, pp. 129-132, 134, 136, www.optoelectronics-world.com			
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		NIKOONAHAD, MEHRDAD, ET AL., In Situ Height Correction For Laser Scanning of Semiconductor Wafers, Optical Engineering, October 1995, Vol 34, No. 10, pp. 3036-3039			
		MONTAGU, Galvanometric and Resonant Low Inertia Scanners, Laser Beam Scanning, Marcel-Dekker, 1985, pgs. 214-216			
		PCT International Preliminary Examination Report, dated 15 Mar 2004, pp. 1-4			
	SMH		PCT International Preliminary Examination Report, dated 28 Aug 2003, pp. 1-4		

Examiner Signature	S. Hemminger	Date Considered	04-06-05
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		Number	Kind Code ² (if known)			
SMH		4,156,124		Macken, et al.	05/22/1979	
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		Office ³	Number ⁴	Kind Code ⁵ (if known)				
SMH		WO	96/16767		Komatsu Ltd.	06/06/1996		
SMH		WO	98/53949		SDL, Inc.	03/12/1998		

Examiner Signature	Samuel M. Hammer	Date Considered	04-06-05
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Sheet	2	of	3	Attorney Docket Number	GSIL 0117 PUSA 1

U.S. PATENT DOCUMENTS

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Examiner Signature	S. Herring	Date Considered	040605
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SMH		MONTAGU, Galvanometric and Resonant Low Inertia Scanners, Laser Beam Scanning, Marcel-Dekker, 1985, pgs. 214-216			
SMH		HAYES, ORLAN, Marking Applications Now Encompass Many Materials, Laser Focus World, February 1997, pgs. 153-160			
SMH		ROSSI, BRIAN, Commercial Fiber Lasers Take On Industrial Markets, Laser Focus World, May 1997, pgs. 143-150			
SMH		Invention Disclosure entitled "Calibration System For Fine Die Alignment", shipping date 9/98 to Hewlett Packard			

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